

Features

- Low on resistance
- Low reverse transfer capacitances
- 100% single pulse avalanche energy test
- 100% ΔVDS test
- Pb-Free plating / Halogen-Free / RoHS compliant

Key Parameters

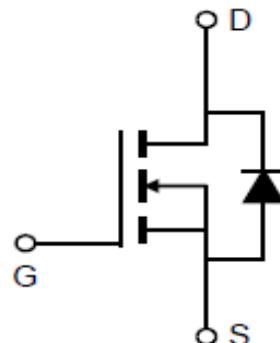
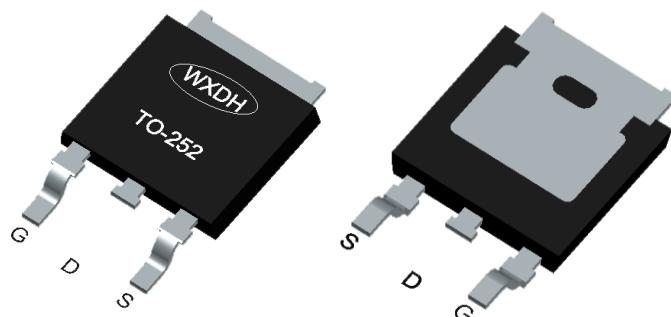
V _{DS}	68V
R _{DS(on)typ.}	7.2mΩ
I _D	80A
V _{th}	3V
C _{iss@10V}	2859pF
Q _{gd}	19nC

Applications

- Motor Control and Drive
- Charge/Discharge for Battery Management System
- Synchronous Rectifier for SMPS



TO-252



Marking & Packing Information

Part #	Package	Marking	Tube/Reel	Qty(pcs)
DTD080N07N	TO-252	DTD080N07N	Tape & Reel	2500/box

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	68	V
Gate-Source voltage	V _{GS}	±20	V
Continuous drain current	I _D	80	A
T _C = 25°C		51	
T _C = 100°C			
Pulsed drain current (T _C = 25°C, t _p limited by T _{jmax})	I _D pulse	320	A
Avalanche energy, single pulse (L=0.5mH, R _g =25Ω) ⁽¹⁾	E _{AS}	289	mJ
Power dissipation	P _{tot}	89	W
T _A = 25°C		1.7	W
Operating junction and storage temperature	T _j , T _{stg}	-55...+150	°C

Notes: 1. EAS was tested at T_j = 25°C, L = 0.5mH, I_d=24A.

Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R _{thJC}	1.4	°C/W
Thermal resistance, junction – ambient(min. footprint)	R _{thJA}	75	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Static Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Drain-source breakdown voltage	BV _{DSS}	68	-	-	V	V _{GS} =0V, I _D =250uA
Gate threshold voltage	V _{GS(th)}	2.0	3.0	4.0	V	V _{DS} =V _{GS} , I _D =250uA
Zero gate voltage drain current	I _{DSS}	-	-	1	μA	V _{DS} =68V, V _{GS} =0V
		-	-	100		T _j =25°C T _j =125°C
Gate-source leakage current	I _{GSS}	-	-	100	nA	V _{GS} =20V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	7.2	8.0	mΩ	V _{GS} =10V, I _D =30A, T _j =25°C
Transconductance	g _{fs}	-	36	-	S	V _{DS} =5V, I _D =30A

Dynamic Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Input Capacitance	C _{iss}	-	2859	-	pF	V _{GS} =0V, V _{DS} =35V, f=1MHz
Output Capacitance	C _{oss}	-	193	-		
Reverse Transfer Capacitance	C _{rss}	-	160	-		
Gate Total Charge	Q _G	-	59	-	nC	V _{GS} =10V, V _{DS} =35V, I _D =30A
Gate-Source charge	Q _{gs}	-	17	-		
Gate-Drain charge	Q _{gd}	-	19	-		
Gate plateau voltage	V _{plateau}	-	5.8	-	V	
Turn-on delay time	t _{d(on)}	-	13	-	ns	V _{GS} =10V, V _{DD} =35V, R _{G_ext} =3Ω
Rise time	t _r	-	28	-		
Turn-off delay time	t _{d(off)}	-	34	-		
Fall time	t _f	-	11	-		
Gate resistance	R _G	-	1.4	-	Ω	V _{GS} =0V, V _{DS} =0V, f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Diode Max Current	I _S		-	80	A	-
Diode Forward Voltage	V _{SD}	-	-	1.2	V	V _{GS} =0V, I _{SD} =30A
Diode Reverse Recovery Time	t _{rr}	-	29	-	ns	I _F =30A, dI/dt=100A/μs
Diode Reverse Recovery Charge	Q _{rr}	-	21	-		

Typical Characteristics Diagram

Fig1. Output Characteristics

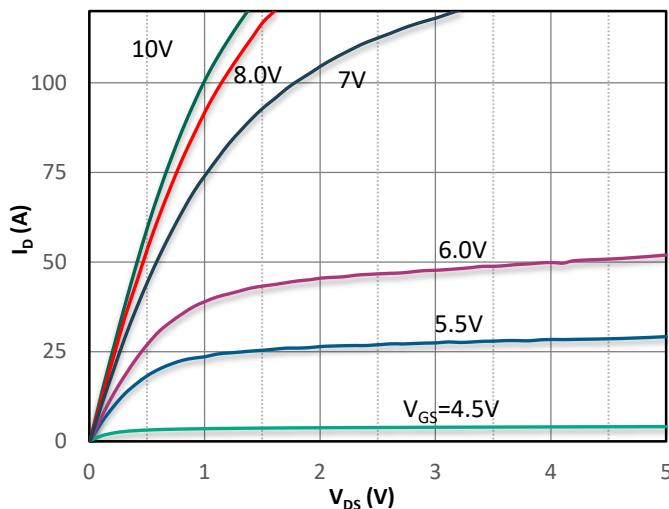


Fig2. Transfer Characteristics

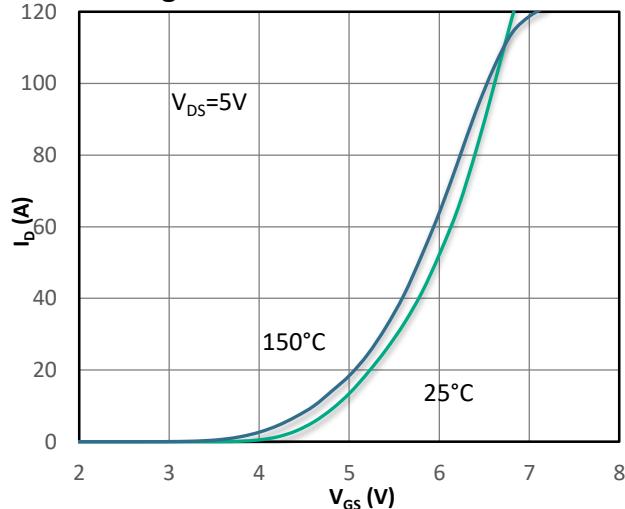


Fig3. R_{ds(on)} vs Drain Current

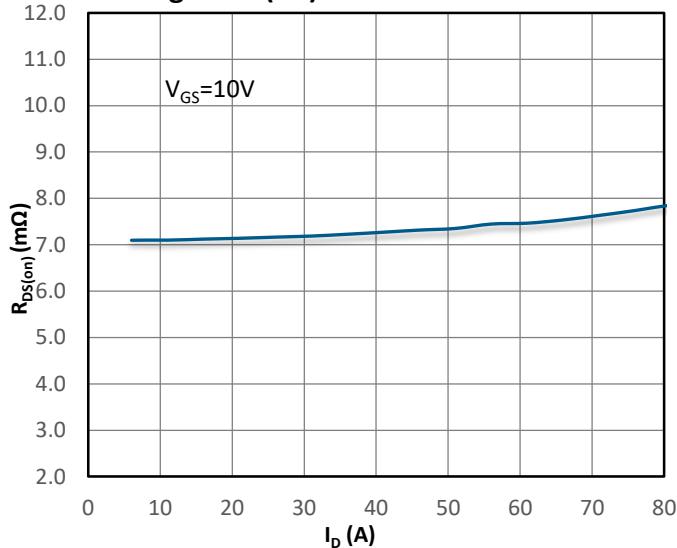


Fig 4. R_{ds(on)} vs Gate Voltage

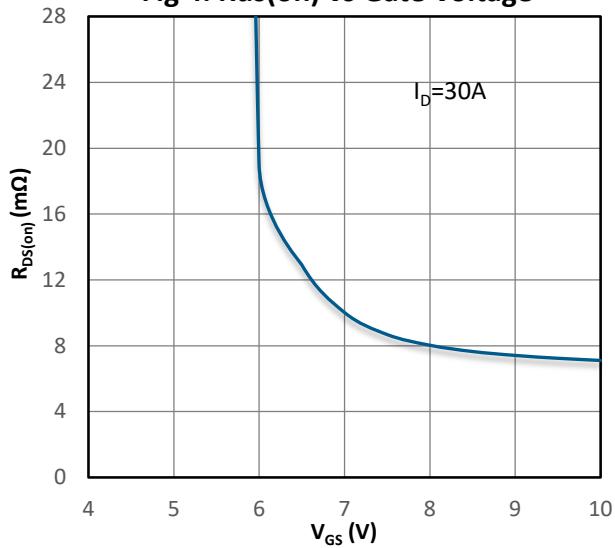


Fig5. R_{ds(on)} vs. Temperature

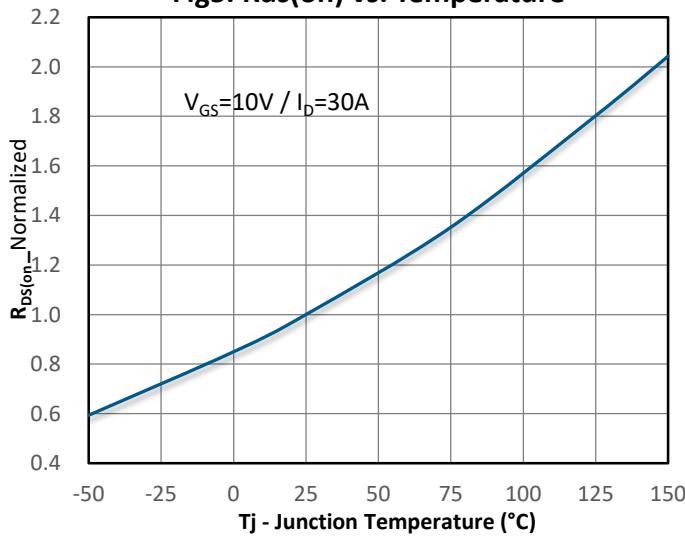
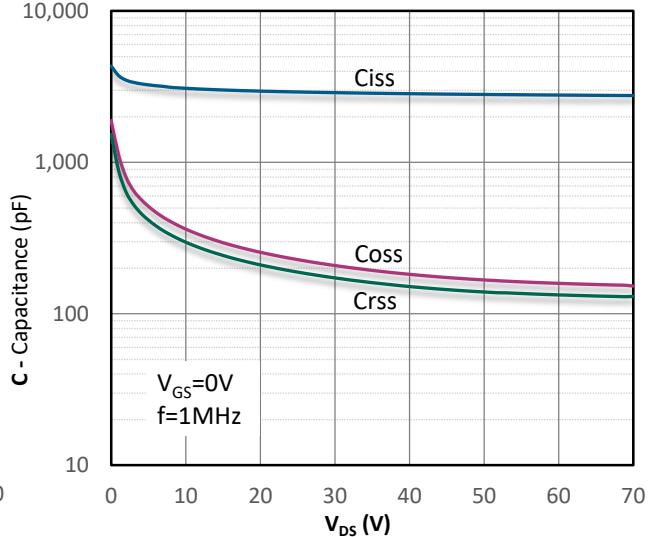


Fig6. Capacitance Characteristics



Typical Characteristics Diagram

Fig7. Gate Charge Characteristics

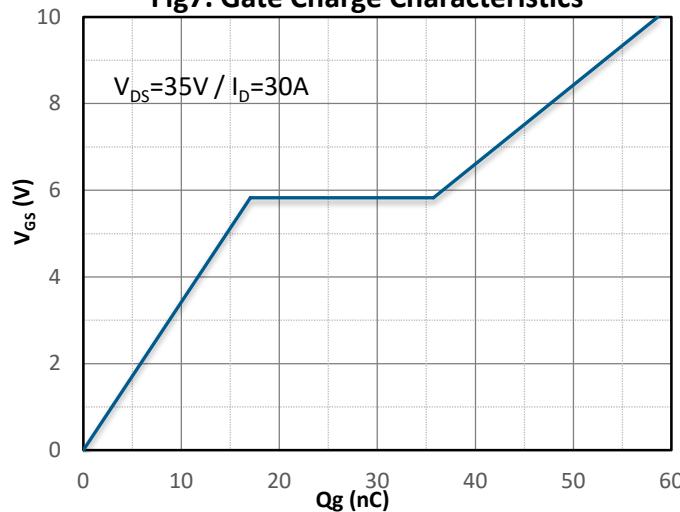


Fig8. Body-diode Forward Characteristics

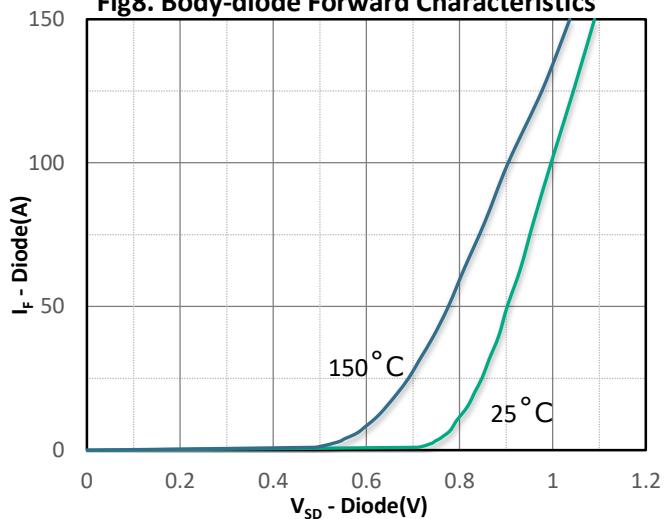


Fig9. Power De-rating

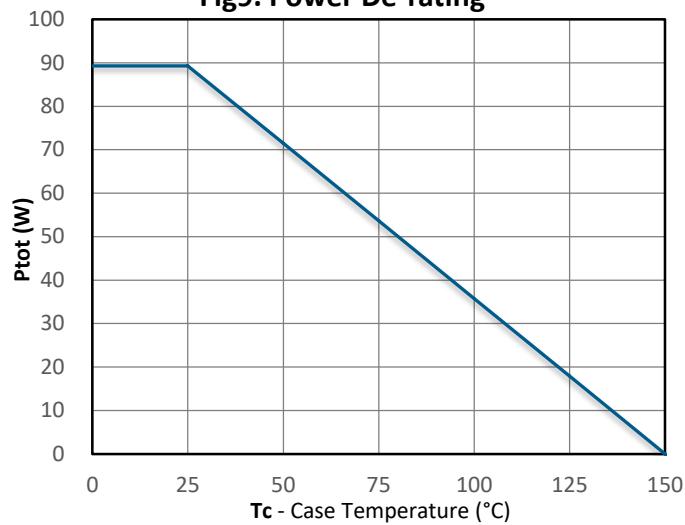


Fig10. Current De-rating

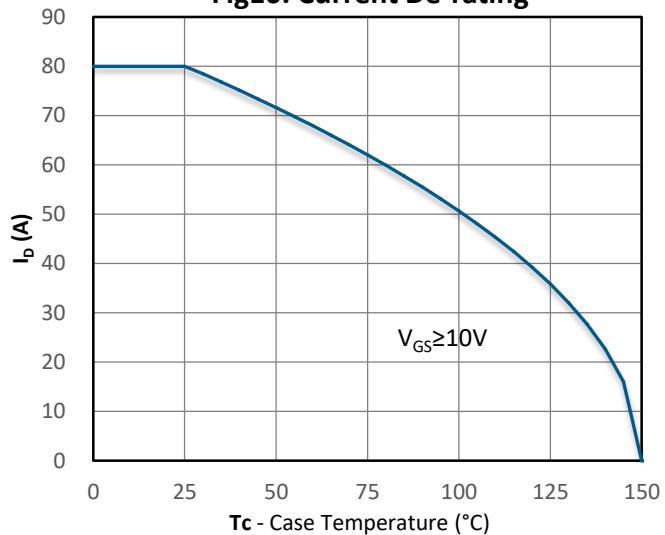


Fig11. Safe Operating Area

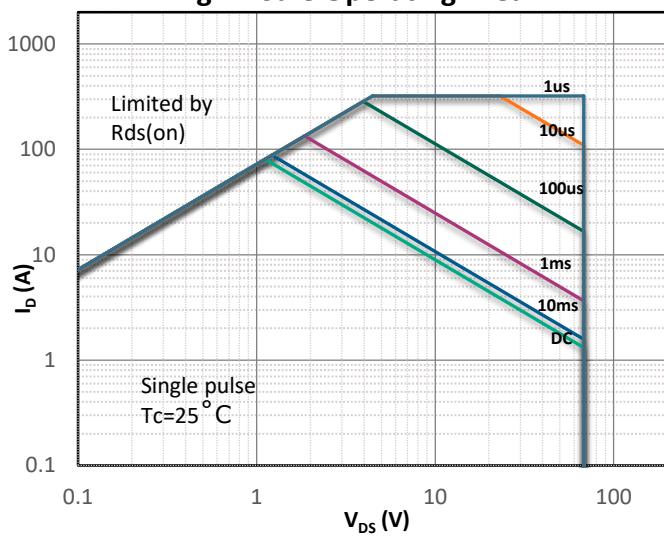
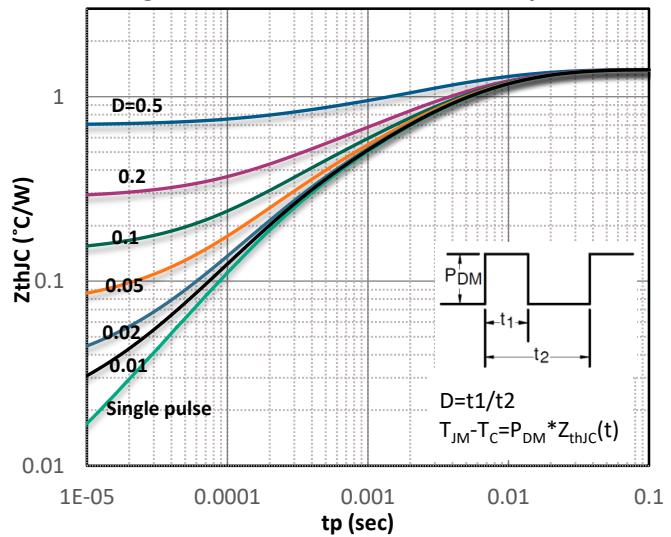
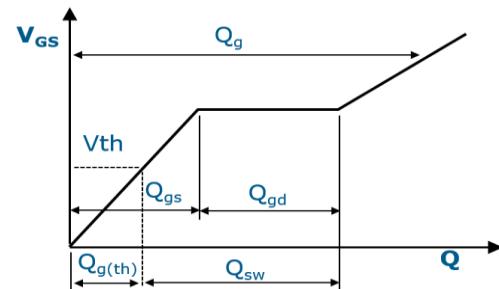
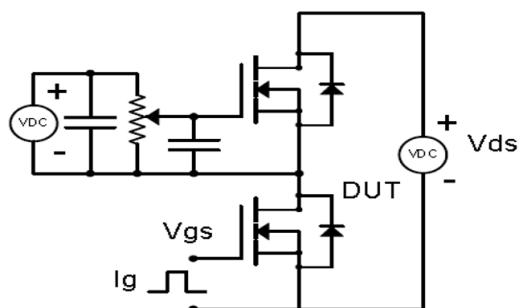


Fig12. Max. Transient Thermal Impedance

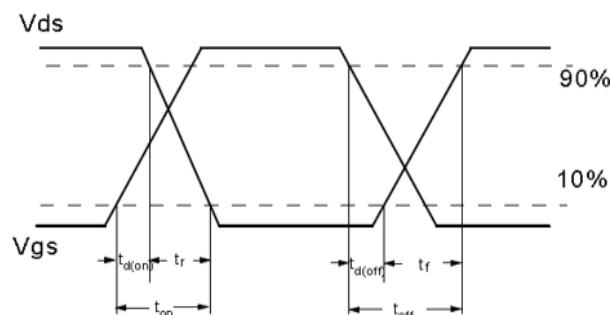
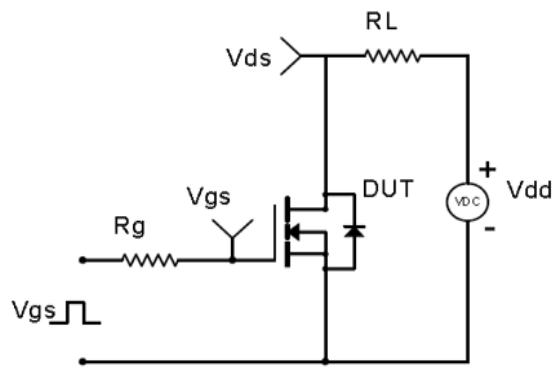


Test Circuit & Waveform

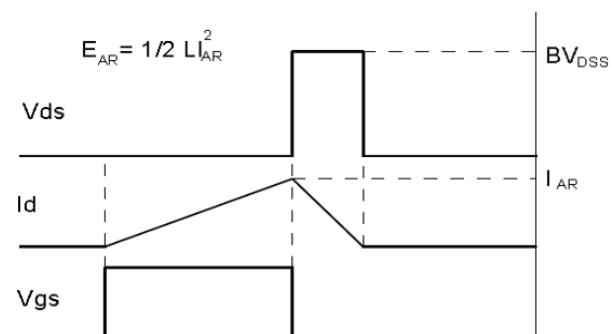
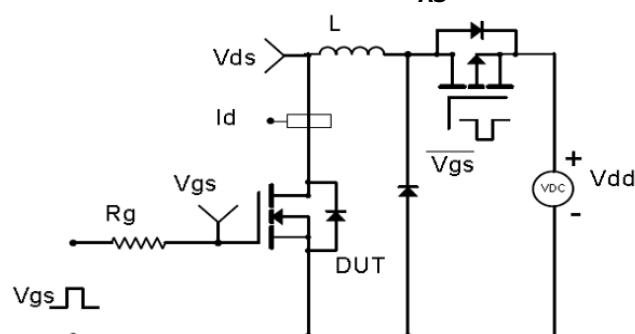
Gate Charge Test Circuit & Waveform



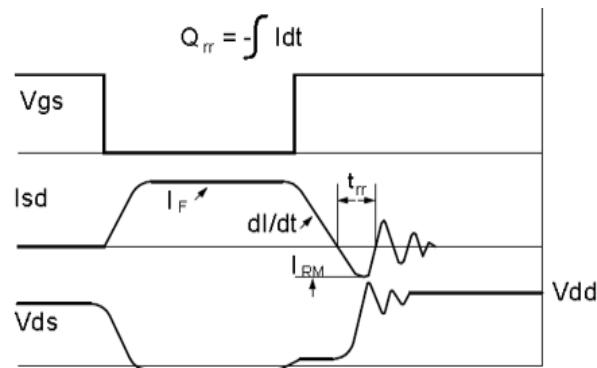
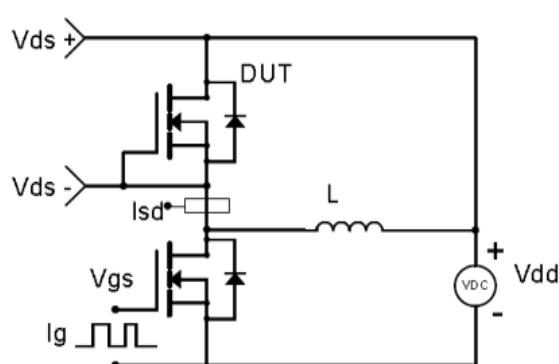
MOSFET Switching Test Circuit & Waveform



E_{AS} Test Circuit & Waveform

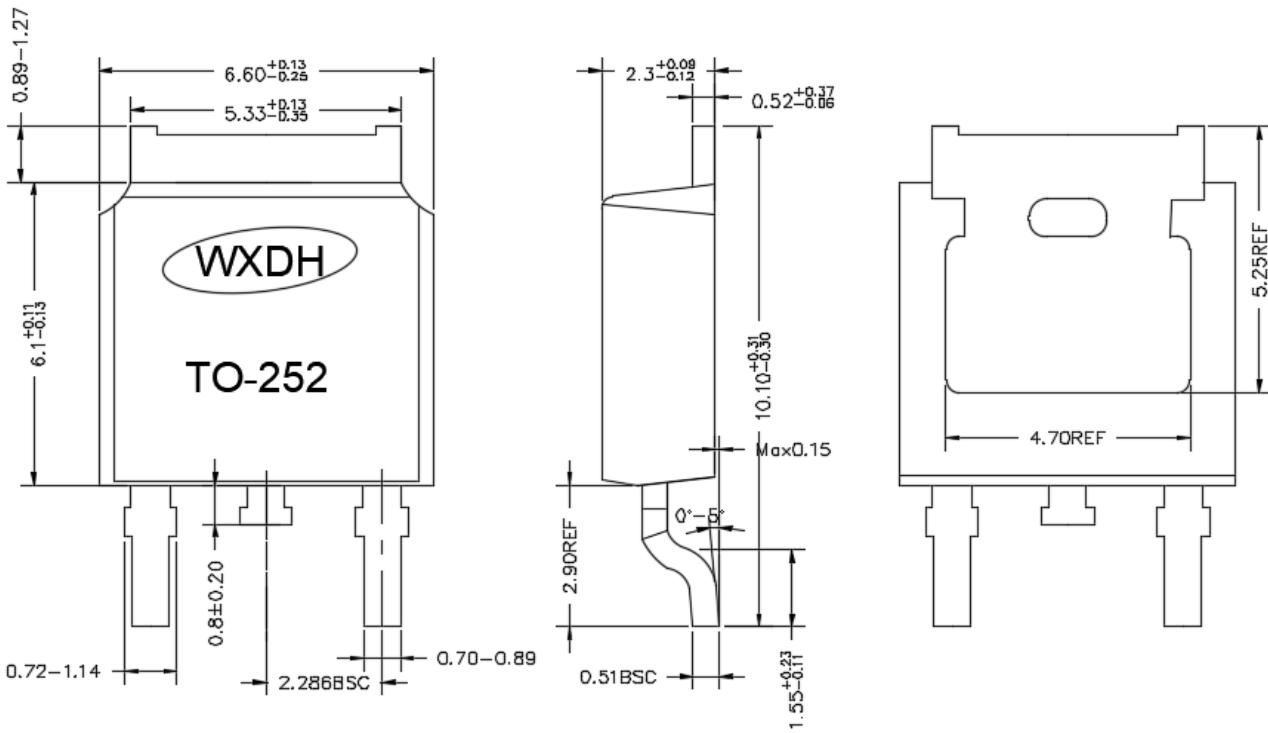


Diode Recovery Test Circuit & Waveform



Package Outline : TO-252

*Dimensions in mm



Revision History

Revison	Date	Major changes
1.0	2023/6/5	Release of formal version

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as aviation, aerospace, life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are responsible for providing adequate safe measures when design their systems.

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